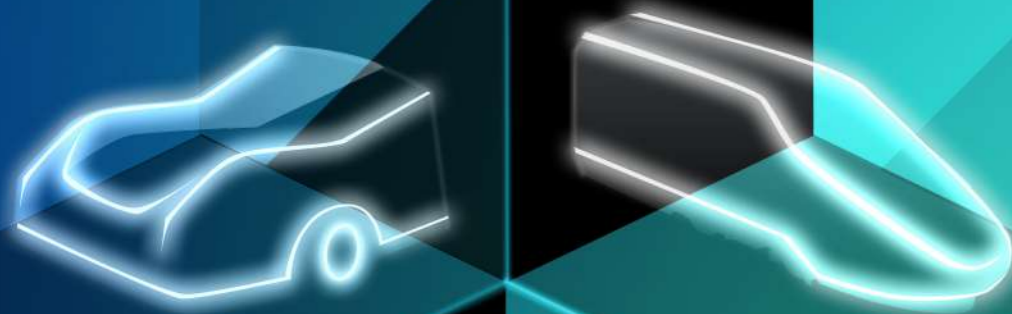


# Metromest

International Conference on  
Industrial Dimensional Metrology

15<sup>th</sup>  
ANNIVERSARY  
Edition



10 + 11 + 12  
APRIL  
2019  
Bilbao / SPAIN

www.metromeet.org

April **10** Abril

08:30 - 09:00	Registration + Coffee
09:00 - 11:30	<b>TUTORIAL 1</b> Towards Intelligent Zero Defects Manufacturing <b>Toni Ventura-Traveset   Datapixel (Spain)</b>
11:30 - 12:15	Coffee Break + <b>INNOVALIA METROLOGY MetroLab</b>
12:15 - 12:30	<b>OPENING</b>
12:30 - 13:30	<b>KEYNOTE</b> QIF – Enabling Interoperable Manufacturing and Quality throughout Supply Chain <b>Ray Admire   QIF Solutions / DMSC (United States)</b>
13:30 - 15:00	Lunch · <b>Jauregia Restaurant</b>
15:00 - 17:00	<b>TRACK 1 · Industrial Metrology Applications</b>
15:00 - 15:30	Automatic multispectral inspection system for corrosion and coatings <b>Bart Ribbens   Antwerp University (Belgium)</b>
15:30 - 16:00	Future Directions in Hot Metrology and Non Destructive Testing for Additive Manufacturing <b>William Kerr   Advanced Forming Research Centre (United Kingdom)</b>
16:00 - 16:30	Micro Coordinate Measurement Machine (mCMM) using voice coil actuator with interferometric position feedback <b>Gabor Molnar   PTB (Germany)</b>
16:30 - 17:00	Towards superresolution surface metrology <b>Samanta Piano   Nottingham University (United Kingdom)</b>
17:00 - 17:30	<b>SPECIAL LECTURE 1</b> Manufacturing on Demand <b>Philip Hewitt   Autodesk (United Kingdom)</b>
17:30 - 18:30	<b>TRACK 2 · Instrumentation and Calibration</b>
17:30 - 18:00	Practical ways for ensuring the validity of measurements results <b>Adriana Valcu   Regional Directorate of Legal Metrology (Romania)</b>
18:00 - 18:30	Assessment and selection of existing methods for calibrating coordinate measuring machines <b>Yuliia Skovorodkina   National Scientific Center Institute of Metrology (Ukraine)</b>
20:30 - 23:00	Conference Banquet · <b>Sociedad Bilbaína</b>

\*Simultaneous translation of all presentations will be made available to all attendees. / Todas las presentaciones tendrán traducción simultánea.  
\*The organization reserves the right to reschedule, add or cancel presentations. / La organización se reserva el derecho a modificar horarios, añadir o cancelar presentaciones.

April **11** Abril

08:30 - 09:00	Registration
09:00 - 11:30	<b>TUTORIAL 2</b> Measuring in machine tool <b>Ainhoa Etxabari   Innovalia Metrology (Spain)</b>
11:30 - 12:15	Coffee Break + <b>CIN ADVANCED SYSTEMS MetroLab</b>
12:15 - 13:15	<b>TRACK 3 · Advanced Calibration</b>
12:15 - 12:45	Equipment calibration, qualification and validation, the customer's role <b>Jan Lasso Andreasen   Novo Nordisk (Denmark)</b>
12:45 - 13:15	Extrinsic calibration and kinematic modelling of a laser line triangulations sensor integrated in an intelligent fixture with 3 degrees of freedom <b>Ahmed Chekh   Tekniker (Spain)</b>
13:15 - 15:00	Lunch · <b>Jauregia Restaurant</b>
15:00 - 16:00	<b>TRACK 4 · Metrology 4.0</b>
15:00 - 15:30	Computer Aided Technologies for Additive Manufacturing – CAxMan <b>Jean-Claude Morel   Topsolid (France)</b>
15:30 - 16:00	Integrated Information for Improved Quality Demonstrators <b>Toby Maw   MTC (United Kingdom)</b>
16:00 - 16:30	<b>SPECIAL LECTURE 2</b> The design and fabrication of the Multi Link Inspection tool <b>Gabriele D'amico   F4E (Italy)</b>
16:30 - 18:30	<b>TRACK 5 · Industrial Metrology Solutions</b>
16:30 - 17:00	Digital thread through International standards <b>Alain Pfouga   Prostep ivip Association (Germany)</b>
17:00 - 17:30	Nanoanalysis for the semiconductor industry <b>Narciso Gambacorti   CEA (France)</b>
17:30 - 18:00	Hybrid active control devices with transparent and high-strength tips for contact and non-contact measurement of product sizes with discontinuous surfaces <b>Evgeny Leun   Lavochnik Association (Russia)</b>
18:00 - 18:30	A systematic approach to metrology for additive manufactured components for advanced industrial applications <b>Andy Townsend   EPSRC Future Metrology Hub (United Kingdom)</b>
18:30 - 19:00	<b>MANUFACTURING STANDARDS ROUND TABLE + CLOSING</b>

April **12** Abril

<p><b>Metromest and Wine</b></p> <p>In this <b>15th anniversary edition of Metromest</b> we will have an <b>extra day focused on the role of Metrology in the racing field</b>. On <b>April 12th</b> Metromest will give you the opportunity to discover some real applications and metrology developments for the racing world while discovering the secrets of a true Spanish Winery.</p> <p>En la edición <b>15 aniversario de Metromest</b> contaremos con un <b>tercer día lleno de sorpresas focalizado en el papel de la Metrología en el mundo deportivo</b>. Durante el <b>12 de abril</b>, te damos la oportunidad de conocer aplicaciones reales de Metrología en el sector más competitivo mientras descubres los secretos de una típica bodega española.</p>	
08:30	<b>Departure from Euskalduna Conference Centre</b>
09:00 - 10:00	<b>Trip to the winery + Welcome</b>
10:00 - 10:30	<b>Metrology in Races</b> Importance of Metrology in the bike racing field <b>Sara García   Spanish TT Rally Champion in 2016 and 2017 and first woman in Dakar 2019 Malle Moto (Spain)</b>
10:30 - 11:00	<b>Coffee Break</b>
11:00 - 12:30	<b>The Future of Metrology</b>
11:00 - 11:30	Calibration technology for tomography <b>Jon Martin &amp; Naiara Ortega   Innovalia &amp; UPV/EHU - CFAA (Spain)</b>
11:30 - 12:00	Think outside the box: A scalable computing device for the smart factory <b>Edwin Popp   LMI Technologies (Germany)</b>
12:00 - 12:30	Advanced 3D measurements with Conoscopic Holography <b>Ignacio Alvarez   Cin Advanced Systems Group (Spain)</b>
12:30 - 13:00	Adalam: Developing an adaptive laser micromachining system <b>Silvia de la Maza   Innovalia (Spain)</b>
13:00 - 13:10	<b>CLOSING</b>
13:10 - 13:50	<b>Winery Tour</b>
14:00 - 15:30	<b>Lunch</b>
15:30 - 16:30	<b>Journey back to Bilbao</b>